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# **RF Exposure Report**

Applicant Name: SAMSUNG Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-Si, Gyeonggido, 16677 Rep. of Korea Date of Issue: Jul. 09, 2020 Test Report No.: HCT-SR-2006-FC021-R1 Test Site: HCT CO., LTD.

FCC ID:	A3LSMN980F
Equipment Type:	Mobile Phone
Application Type	Certification
FCC Rule Part(s):	FCC Part 1 SUBPART I FCC Part 2 SUBPART J KDB 680106 D01
Model Name:	SM-N980F/DS
Additional Model Name:	SM-N980F
Date of Test:	06/23/2020

This device has been shown to be capable of compliance for the above standars for uncontrolled environment/general population exposure limits specified in FCC KDB procedures and had been tested in accordance with the measurement procedures specified in FCC KDB procedures.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

**Tested By** 

Jung Hun, Park Test Engineer SAR Team Certification Division

**Reviewed By** 

no

Yun-jeang, Heo Technical Manager SAR Team Certification Division

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## **DOCUMENT HISTORY**

Rev.	DATE	DESCRIPTION	
0	06. 30, 2020	First Approval Report	
R1	07. 09. 2020	Revised TYPO Page 5,6 and 8	



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## 1. Test Methodology

The DUT was assessed in accordance with FCC KDB 680106 D01 RF Exposure Wireless Charging App v03.

## 2. Test Location.

## 2.1 Test Laboratory.

Company Name:	HCT Co., LTD
Address:	74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si, Gyeonggi-do, 17383, Rep. of Korea
Telephone:	+82 31 645 6300
Fax.:	+82 31 645 6401

#### 2.2 Test Facillities

Our laboratories are accredited and approved by the following approval agencies according to ISO/IEC 17025.

Kana	National Radio Research Agency (Designation No. KR0032)
Korea:	KOLAS (Tesing No. KT197)



## 3. DEVICE UNDER TEST DESCRIPTION

Applicant Name:	SAMSUNG Electronics Co., Ltd.	
Model:	SM-N980F/DS	
Additional Model Name:	SM-N980F	
EUT Type:	Mobile Phone	
Application Type:	Certification	

#### 3.1 Description of DUT

The DUT is a mobile phone with a WPT (Wireless Power Transfer) feature using an inductive charging coil to charge a phone or watch. The charing frequency is between 110 kHz to 148 kHz, and the maximum transfer power consumption is 9.0 W in charging status.

SM-N980F/DS, SM-N980F were tested and the worst case results are reported. (Worst case : SM-N980F/DS)

#### 3.2 WORST-CASE CONFIGYRATION

Test configration	Description
DUT to Phone test configuration 1	Charging from Phone to DUT
DUT to Phone test configuration 2	Charging from Phone to DUT( TA Carging from DUT)
DUT to Phone test configuration 3	Charging from Phone to DUT
DUT to Phone test configuration 4	Charging from Phone to DUT( TA Carging from DUT)
DUT to Phone test configuration 5	Charging from Watch to DUT
DUT to Phone test configuration 6	Charging from Watch to DUT(TA Carging from DUT)

Note :

1. Configuration 2,4 and 6 were tested with the worst case of configuration 1,3 and 5

2. All test configurations are with s-Pen inserted for charging.



## 3.3 KDB 680106 D01 v03 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device
(1) Power transfer frequenct is less than 1 MHz.	Yes. Operation Frequency is between 110 kHz to 148 Khz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
<ul> <li>(3) The transfer system includes onlt single primary and secondart coils.</li> <li>This includes charging systems that may have multiple primary coils and client that are able to detect and allow coupling only between individual pairs of coils</li> </ul>	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile expousure conditions only(portable exposure conditions are not convered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field is 7.91 % of the FCC H field limit.



## 3.4 DESCRUPTION OF TEST SETUP SUPPORT EQUIPMENT & PERIPHERALS

SUPPORT EQUIPMENT & PERIPHERALS LIST						
Description	Description Manufacturer		Serial Numver	FCC ID		
Watch	SAMSUNG Electronics Co., Ltd.	SM-R835F	RFAM80Q6NJW	A3LSMR835		
Phone SAMSUNG Electronics Co., Ltd.		SM-G986B/DS	RF8M70ZA4FH	A3LSMG986B		
Travel Adapter	Solu-M	EP-TA800	-			
USB Data Cable	RF Tehck	EP-DG980BBE				

### TEST SETUP

The following three modes are tested in test configuration;

Mode
Operationg
(SUPPORT Equipment, <10% Power Charging)
Operationg
(SUPPORT Equipment, 50~55% Power Charging)
Operationg
(SUPPORT Equipment, 90~95% Power Charging)



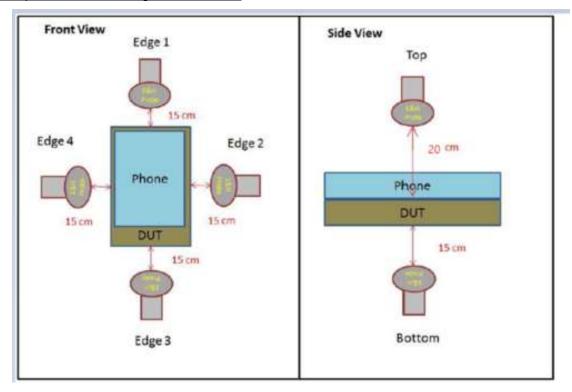
#### For Simultaneous Charging

All Position of client device were investigated and the worst position results are reported. For S-Pen, both fully charged and non-fully charged condition were investigated. Test wer performed nonfully charged condition as worst case. Please refer to S-Pen Test report

#### **MEASUREMENT TEST SETUP**

The measurement was taken using a probe place 15 cm from the edges of DUT or20 cm above the DUT. Measurement were from the top and all sides of the DUT per KDB680106 D01 v03. Additionally, as the DUT to phone configuration could result with the DUT place either above or below the phone, measurements were performed 'below' th DUT by flipping the DUT/phone so that the DUT was uppermost.

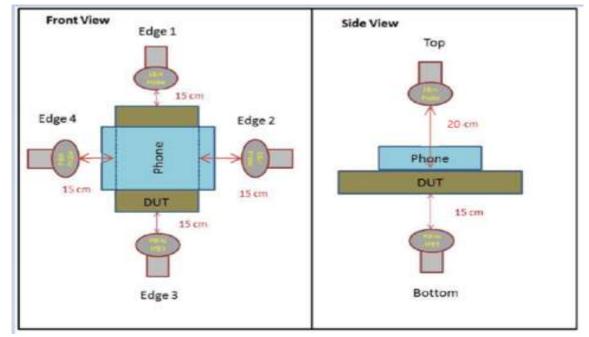
The probe was moved along the edges or above the DUT to a position that showed the maximum field strength. This position was used for the reported resul.



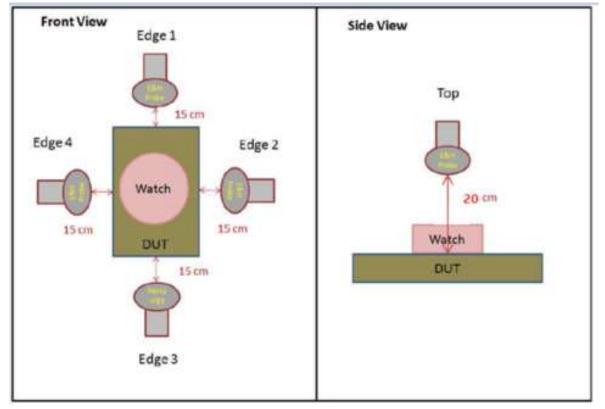
#### DUT to phone test Configuration 1 & 2



## DUT to phone test Configuration 3 & 4



### DUT to phone test Configuration 5 & 6





## 4. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report :

Manufacturer	Model namr	Description	S/N	Calib. Date	Calib.Due
Narda	EHP-200AC	Electric and Magnetic Field Probe	170WX91009	11/22/2019	11/22/2020

## 5. MAXIMUM PERMISSIBLE RE EXPOSURE

#### 5.1 FCC RULES

1.13010 The criteria listed in Table 1 shall be used to evaluate the envirimental impact of human exposure to radio-frequency(RF) ragiation as specified in 1.1307(b), except in the case of portable devices which shall ge evaluated according th the provisions of 2.1093 of this chapter.

#### TABLE 1-LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)
(A) Lim	its for Occupational	/Controlled Exposur	es	
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842 <i>/</i> f	4.89/f	*(900/f2)	6
30–300	61.4	0.163	1.0	(
300–1500			f/300	6
1500–100,000			5	6
(B) Limits	for General Populati	on/Uncontrolled Exp	osure	
0.3–1.34	614	1.63	*(100)	30
1.34–30	824 <i>/</i> f	2.19/f	*(180/f <sup>2</sup> )	3(

#### TABLE 1-LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)-Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300-1500			f/1500	30
1500-100,000		*****	1.0	30

f = frequency in MHz

\* = Plane-wave equivalent power density NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occu-tion is a situation of the exposure also apply in situations when an individual is transient through a location where occu-tion is a situation of the exposure also apply in situations when an individual is transient through a location where occu-tional for exposure and the exposure also apply in situations.

pational/controlled limits apply provided he or she is made aware of the potential for exposure. NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be ex-posed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.



# 6. TEST RESULTS

#### H-Field Measurements

Note : peak measurements were performed. RMS values were calculated from the peak measurement. Please refer to the formula for calculating the RMS value: [Field Strength \* \/Duty Cycle]

#### TEST results of DUT to phone test Comfiguration 1 &2

FCC RF Exposurs Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
		20 cm	Тор		0.0952
			Bottom		0.1243
	Operation Real Product		Edge 1	1.63	0.1240
	(Power <10% charging)	15 cm	Edge 2	1.63	0.1260
			Edge 3		0.1236
			Edge 4		0.1247
		20 cm	Тор		0.0951
			Bottom		0.1243
Configuration 1	Operation Real Product		Edge 1	1.63	0.1239
	(Power 50~55% charging)	15 cm	Edge 2	1.05	0.1258
			Edge 3		0.1231
			Edge 4		0.1243
		20 cm	Тор		0.0947
			Bottom		0.1242
	Operation Real Product		Edge 1	1.63	0.124
	(Power 90~95% charging)	15 cm	Edge 2	1.05	0.1259
			Edge 3		0.1231
			Edge 4		0.1246
Configuration 2	Operation Real Product	15 cm	Edge 2	1.63	0.1243
Configuration 2	(Power <10% charging)		Euge 2		0.1243



FCC RF Exposurs Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
		20 cm	Тор		0.0935
			Bottom		0.1220
	Operation Real Product		Edge 1	1.63	0.1249
	(Power <10% charging)	15 cm	Edge 2	1.05	0.1250
			Edge 3		0.1289
			Edge 4		0.1218
		20 cm	Тор	1.63	0.0933
Configuration 3	Operation Real Product	15 cm	Bottom		0.1215
			Edge 1		0.1247
	(Power 50~55% charging)		Edge 2		0.1247
			Edge 3		0.1284
			Edge 4		0.1215
		20 cm	Тор		0.0935
			Bottom		0.1218
	Operation Real Product		Edge 1	1.63	0.1248
	(Power 90~95% charging)	15 cm	Edge 2		0.1248
			Edge 3		0.1287
			Edge 4		0.1215
Configuration 4	Operation Real Product (Power <10% charging)	15 cm	Edge 3	1.63	0.1225

## TEST results of DUT to phone test Comfiguraion 3 &4



FCC RF Exposurs Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
		20 cm	Тор		0.0954
	Operation Real Product	15 cm	Edge 1	1.63	0.1231
			Edge 2		0.1243
	(Power <10% charging)		Edge 3		0.1252
			Edge 4		0.1256
	Operation Real Product (Power 50~55% charging)	20 cm	Тор	1.63	0.0950
Configuration 5		15 cm	Edge 1		0.1225
			Edge 2		0.1239
			Edge 3		0.1250
			Edge 4		0.1251
		20 cm	Тор		0.0949
Operation Real (Power 90~95%	Operation Real Product	15 cm	Edge 1	1.63	0.1229
			Edge 2		0.1239
	(Fower 30~35 % charging)		Edge 3		0.1247
			Edge 4		0.1251
Configuration 6	Operation Real Product (Power <10% charging)	15 cm	Edge 4	1.63	0.1254

## TEST results of DUT to phone test Comfiguraion 5 &6

## 6.2 FCC SUMMARYOF RESULTS

H-Field Limit				
FCC RF Exposure	Maximum meas data (A/m)	Percentage(%)		
1.63	0.1289	7.91		

H-Field test result was less than 50% of MPE limit